

2011 IEEE International Instrumentation and Measurement Technology Conference

Four Points by Sheraton Hangzhou, Binjiang
Hangzhou, P. R. China
May 10-12, 2011

Call for Papers

The Conference focuses on all aspects of instrumentation and measurement science and technology—research, development and applications. The program topics include but are not limited to:

FUNDAMENTALS

Theoretical foundations
Quantities, units & standards
Calibration & self-calibration
Measurement uncertainty
Methodology of teaching
Modeling of signals and systems

SENSORS AND TRANSDUCERS

Smart sensors and sensor networks
Optical, chemical and biological sensors
Wireless sensors
Sensor arrays
Energy harvesting
Sensor standards
Sensor applications

MEASUREMENTS OF PHYSICAL QUANTITIES

Electrical & power measurements
Dielectric & magnetic measurements
Temperature, moisture & humidity measurements
Mechanical measurements
Optical measurements
Chemical & biological measurements

MEASUREMENT-DATA & SIGNAL PROCESSING

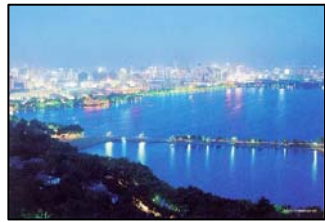
A/D and D/A converters
Analog and mixed signal processing
Data preprocessing & postprocessing
Digital signal processing
Digital image processing
Pattern recognition
Inverse problems & signal reconstruction
Signal detection & classification
Sensor array processing
Data mining and fusion

MEASUREMENT SYSTEMS

Fault-tolerant & resilient measurement systems
Integrated & visual measurement systems
Distributed measurement systems
Autonomous measurement systems
Non-invasive measurement systems
Virtual measurement systems
Measurement microsystems
Human-computer interface
Automated test & diagnostics systems

MEASUREMENT APPLICATIONS

Health care
Food safety and security
Quality assurance and authentication
Renewable energy systems
Carbon capture and storage
Plant optimization
Environmental monitoring
Intelligent buildings
Multiphase flow measurement
Soft sensing and soft computing
Robotics and industrial monitoring
Automotive & transportation
Avionics and aerospace
Ships and marine technology
Medicine and scientific research
Security and biometrics
Telecommunications
Remote sensing



Sponsors



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- **November 15, 2010** – Deadline for submission of extended abstracts.
- **December 20, 2010** – Notification of authors of acceptance or rejection decisions.
- **March 1, 2011** – Deadline for the submission of camera-ready full-text papers.

The extended abstracts will be reviewed by the Technical Program Committee. The authors of accepted papers must register for the Conference and attend to present their papers. The authors of papers, presented during I2MTC 2011, will be allowed to submit expanded and extended versions of their papers to the Special Issue of IEEE Transactions on Instrumentation & Measurement on I2MTC 2011 to be published in 2012.

